

<b>Notice of References Cited</b>	Application/Control No. 09/945,393	Applicant(s)/Patent Under Reexamination MARSH, EUGENE P.	
	Examiner George Fourson	Art Unit 2823	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0045092	03-2005	Wu et al.	117/092
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gan, L., et al, "Dielectric Property of TiO <sub>2</sub> ... thin Films", App. Phys. Lett. 72(3), 1/19/1998, pp. 332-334
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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